

February 1984 Revised July 2003

MM74HC4514 4-to-16 Line Decoder with Latch

General Description

The MM74HC4514 utilizes advanced silicon-gate CMOS technology, which is well suited to memory address decoding or data routing application. It possesses high noise immunity and low power dissipation usually associated with CMOS circuitry, yet speeds comparable to low power Schottky TTL circuits. It can drive up to 10 LS-TTL loads.

The MM74HC4514 contain a 4-to-16 line decoder and a 4-bit latch. The latch can store the data on the select inputs, thus allowing a selected output to remain HIGH even though the select data has changed. When the LATCH ENABLE input to the latches is HIGH the outputs will change with the inputs. When LATCH ENABLE goes LOW the data on the select inputs is stored in the latches. The four select inputs determine which output will go HIGH provided the INHIBIT input is LOW. If the INHIBIT input is HIGH all outputs are held LOW thus disabling the decoder.

The MM74HC4514 is functionally and pinout equivalent to the CD4514BC and the MC1451BC. All inputs are protected against damage due to static discharge diodes from $\rm V_{CC}$ and ground.

Features

- Typical propagation delay: 18 ns
- Low quiescent power: 80 µA maximum (74HC Series)
- Low input current: 1 µA maximum
- Fanout of 10 LS-TTL loads (74HC Series)

Ordering Code:

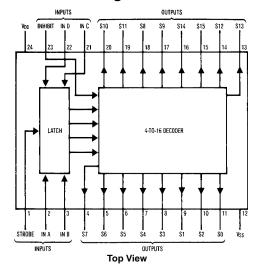
Order Number	Package Number	Package Description
MM74HC4514WM	M24B	24-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide
MM74HC4514MTC	MTC24	24-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 4.4mm Wide
MM74HC4514N	N24C	24-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300" Wide

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

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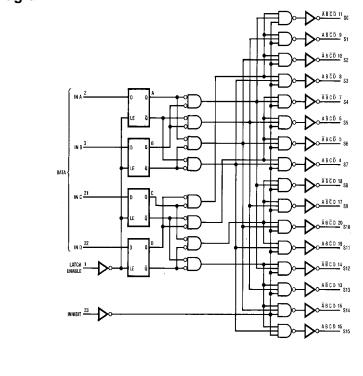
Connection Diagram



Truth Table

			Data I	nputs		
LE	Inhibit	D	С	В	Α	Selected Output High
Н	L	L	L	L	L	S0
Н	L	L	L	L	Н	S1
Н	L	L	L	Н	L	S2
Н	L	L	L	Н	Н	S3
Н	L	L	Н	L	L	S4
Н	L	L	Н	L	Н	S5
Н	L	L	Н	Н	L	S6
Н	L	L	Н	Н	Н	S7
Н	L	Н	L	L	L	S8
Н	L	Н	L	L	Н	S9
Н	L	Н	L	Н	L	S10
Н	L	Н	L	Н	Н	S11
Н	L	Н	Н	L	L	S12
Н	L	Н	Н	L	Н	S13
Н	L	Н	Н	Н	L	S14
Н	L	Н	Н	Н	Н	S15
						All
Χ	Н	Χ	Χ	Χ	Χ	Outputs = 0
						Latched
L	L	Χ	Х	Χ	Χ	Data

Logic Diagram



Absolute Maximum Ratings(Note 1) (Note 2)

Supply Voltage (V_{CC}) -0.5 to +7.0V DC Input Voltage (V_{IN}) -1.5 to V_{CC} +1.5V DC Output Voltage (V_{OUT}) -0.5 to V_{CC} +0.5V Clamp Diode Current (I_{IK} , I_{OK}) ± 20 mA

DC Output Current, per pin (I_{OUT}) ± 25 mA DC V_{CC} or GND Current, per pin (I_{CC}) ± 50 mA Storage Temperature Range (T_{STG}) -65° C to +150 $^{\circ}$ C

Power Dissipation (P_D)

 (Note 3)
 600 mW

 S.O. Package only
 500 mW

Lead Temperature (T_L)

(Soldering 10 seconds) 260°C

Recommended Operating Conditions

	Min	Max	Units
Supply Voltage (V _{CC})	2	6	V
DC Input or Output Voltage	0	V_{CC}	V
(V _{IN} , V _{OUT})			
Operating Temperature Range (T_A)	-40	+85	°C
Input Rise or Fall Times			
$(t_r, t_f) V_{CC} = 2.0V$		1000	ns
$V_{CC} = 4.5V$		500	ns
$V_{CC} = 6.0V$		400	ns
Note 1: Maximum Ratings are those values to	eyond w	hich dama	ge to the

device may occur.

Note 2: Unless otherwise specified all voltages are referenced to ground.

Note 3: Power Dissipation temperature derating — plastic "N" package: –12 mW/°C from 65°C to 85°C.

DC Electrical Characteristics (Note 4)

Symbol	Parameter	Conditions	v _{cc}	T _A = 25°C		$T_A = -40 \text{ to } 85^{\circ}\text{C}$	T _A = -55 to 125°C	Units
Cymbol	i arameter	Conditions	•66	Тур		Guaranteed L	imits	55
V _{IH}	Minimum HIGH Level		2.0V		1.5	1.5	1.5	
	Input Voltage		4.5V		3.15	3.15	3.15	V
			6.0V		4.2	4.2	4.2	
V _{IL}	Maximum LOW Level		2.0V		0.5	0.5	0.5	
	Input Voltage		4.5V		1.35	1.35	1.35	V
			6.0V		1.8	1.8	1.8	
V _{OH}	Minimum HIGH Level	$V_{IN} = V_{IH}$ or V_{IL}	2.0V	2.0	1.9	1.9	1.9	
	Output Voltage	$ I_{OUT} \le 20 \ \mu A$	4.5V	4.5	4.4	4.4	4.4	V
			6.0V	6.0	5.9	5.9	5.9	
		$V_{IN} = V_{IH}$ or V_{IL}						
		$ I_{OUT} \le 4.0 \text{ mA}$	4.5V	4.2	3.98	3.84	3.7	V
		$ I_{OUT} \le 5.2 \text{ mA}$	6.0V	5.7	5.48	5.34	5.2	
V _{OL}	Maximum LOW Level	$V_{IN} = V_{IH}$ or V_{IL}	2.0V	0	0.1	0.1	0.1	
	Output Voltage	$ I_{OUT} \le 20 \ \mu A$	4.5V	0	0.1	0.1	0.1	V
			6.0V	0	0.1	0.1	0.1	
		$V_{IN} = V_{IH}$ or V_{IL}						
		$ I_{OUT} \le 4.0 \text{ mA}$	4.5V	0.2	0.26	0.33	0.4	V
		$ I_{OUT} \le 5.2 \text{ mA}$	6.0V	0.2	0.26	0.33	0.4	
I _{IN}	Maximum Input Current	$V_{IN} = V_{CC}$ or GND	6.0V		±0.1	±1.0	±1.0	μΑ
I _{CC}	Maximum Quiescent Supply Current	$V_{IN} = V_{CC}$ or GND $I_{OUT} = 0 \mu A$	6.0V		8.0	80	160	μА

Note 4: For a power supply of 5V \pm 10% the worst case output voltages (V_{OH} , and V_{OL}) occur for HC at 4.5V. Thus the 4.5V values should be used when designing with this supply. Worst case V_{IH} and V_{IL} occur at $V_{CC} = 5.5V$ and 4.5V respectively. (The V_{IH} value at 5.5V is 3.85V.) The worst case leakage current (I_{IN} , I_{CC} , and I_{OZ}) occur for CMOS at the higher voltage and so the 6.0V values should be used.

AC Electrical Characteristics

 $V_{CC} = 5V,\, T_A = 25^{\circ}C,\, C_L = 15~pF,\, t_r = t_f = 6~ns$

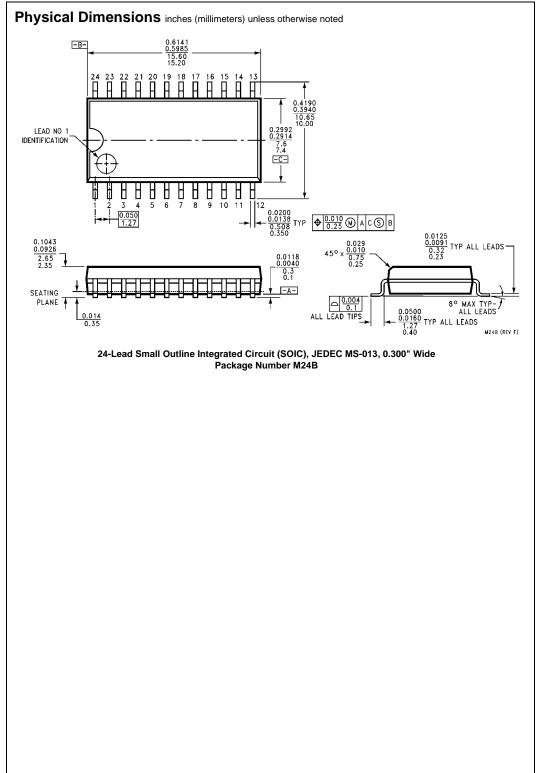
Symbol	Parameter	Conditions	Тур	Guaranteed Limit	Units
t _{PHL} , t _{PLH}	Maximum Propagation Delay Data to Output		18	30	ns
t _{PHL}	Maximum Propagation Delay LE to Output		18	30	ns
t _{PLH}	Maximum Propagation Delay LE to Output		24	40	ns
t _{PHL}	Maximum Propagation Delay Inhibit to Output		16	30	ns
t _{PLH}	Maximum Propagation Delay Inhibit to Output		24	40	ns
t _s	Minimum Setup Time, Date to LE			20	ns
t _H	Minimum Hold Time, LE to Data			5	ns
t _W	Minimum Pulse Width, Latch Enable			16	ns

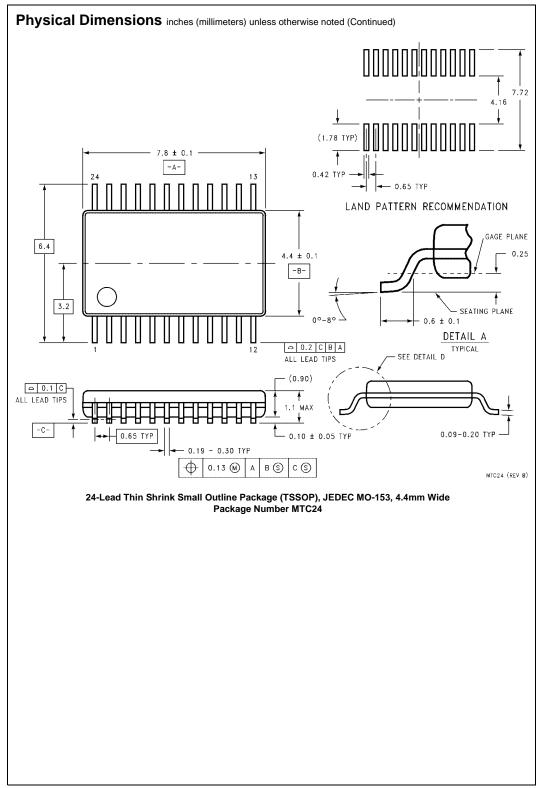
AC Electrical Characteristics

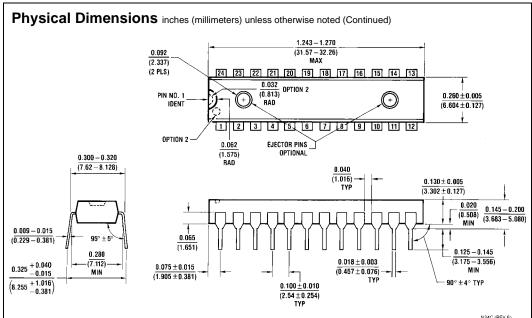
 $\mbox{V}_{CC} = 2.0\mbox{V} - 6.0\mbox{V}, \ \mbox{C}_L = 50 \ \mbox{pF}, \ t_r = t_f = 6 \ \mbox{ns}$ (unless otherwise specified)

Symbol	Parameter	Conditions	v _{cc}	T _A = 25°C		T _A = -40 to 85°C	$T_A = -55 \text{ to } 125^{\circ}\text{C}$	Units
Syllibol				Тур	Typ Guaranteed Limits		Units	
t _{PHL} , t _{PLH}	Maximum Propagation		2.0V	80	175	220	263	
	Delay Data to Output		4.5V	18	35	44	53	ns
			6.0V	16	30	38	45	
t _{PHL}	Maximum Propagation		2.0V	80	175	220	263	
	Delay LE to Output		4.5V	19	35	44	53	ns
			6.0V	17	30	38	45	
t _{PLH}	Maximum Propagation		2.0V	120	230	290	343	
	Delay LE to Output		4.5V	27	46	58	69	ns
			6.0V	22	39	49	58	
t _{PHL}	Maximum Propagation		2.0V	70	175	220	263	
	Delay Inhibit to Output		4.5V	18	35	44	53	ns
			6.0V	16	30	38	45	
t _{PLH}	Maximum Propagation		2.0V	120	230	290	343	
	Delay Inhibit to Output		4.5V	27	46	58	69	ns
			6.0V	22	39	49	58	
t _s	Minimum Setup Time,		2.0V		100	125	150	
	Data to LE		4.5V		20	25	30	ns
			6.0V		17	21	25	
t _H	Minimum Hold Time,		2.0V		5	5	5	
	LE to Data		4.5V		5	5	5	ns
			6.0V		5	5	5	
t _W	Minimum Pulse Width,		2.0V		80	100	120	
	Latch Enable		4.5V		16	20	24	ns
			6.0V		14	17	20	
C _{PD}	Power Dissipation			200				
	Capacitance (Note 5)			290				pF
C _{IN}	Maximum Input		1	5	10	10	10	pF
	Capacitance			5	10	10	10	þΓ

Note 5: C_{PD} determines the no load dynamic power consumption, $P_D = C_{PD} \ V_{CC}^2 \ f + I_{CC} \ V_{CC}$, and the no load dynamic current consumption, $I_S = C_{PD} \ V_{CC} \ f + I_{CC}$.







24-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300" Wide Package Number N24C

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